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AND CTLE FEATURE OPTIMIZATION WITH STATISTICAL ENGINE FOR BER SPECIFICATION







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Outline

- DDR4 feature and design challenge
- > FPGA DDR system design challenge
- > DDR4 statistical simulation method
- **DDR4** De-emphasis and CTLE optimization result discussion

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DDR4 Features

Feature	DDR3	DDR4
Voltage	1.5V	1.2V
Max Datarate (Mbps)	2133	3200
DQ Bus	SSTL15	POD12
DQ Vref	external	Internal
DQ Driver	34 <i>,</i> 40 & 60 (ohm)	34, 40, <mark>48</mark> & 60 (ohm)

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FPGA DDR4 Design Challenges

> DDR4 Design Challenge

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- Higher datarate, Higher loss, intensified ISI

> FPGA Configurable I/O standards

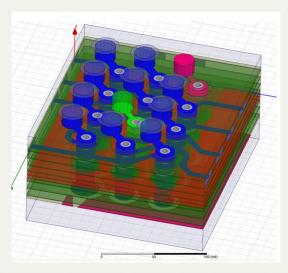
- DDR3, DDR3L, DDR4, LPDDR2, LPDDR3, RLDRAM3, QDR2+, QDR4
- High pad capacitance: FPGA ~3.5pF Vs. ~1.8pF ASIC

FPGA High I/O count

- Up to ~1400 IO counts in Ultrascale family
- High density signal routing
- High signal to ground ratio

> Signal enhancement techniques to mitigate

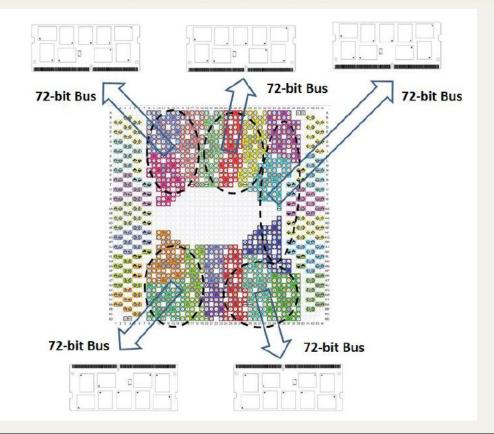
- De-emphasis & CTLE



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FPGA DDR4 Design Challenges

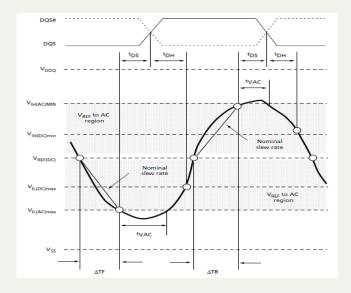
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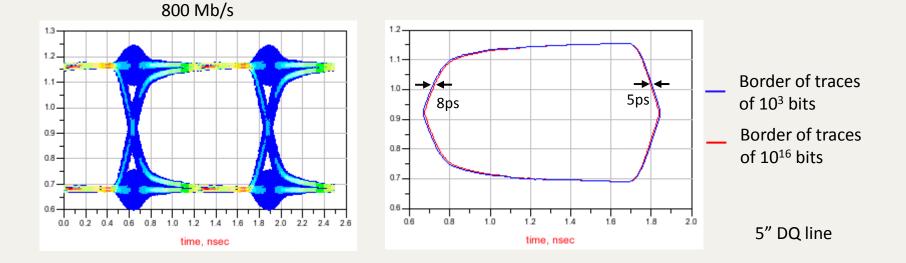
Traditional DDR Design Methodology

- Run transient simulation using IBIS or SPICE models of controller and memory
- Measure setup and hold times on waveforms



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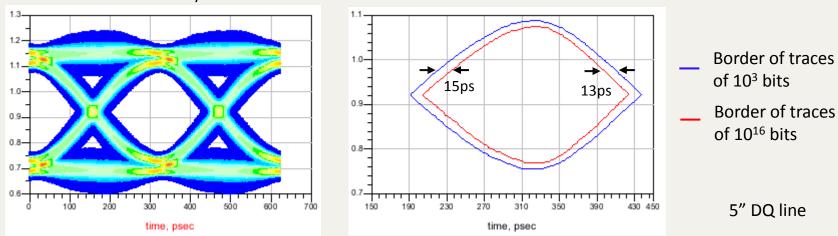
ISI at Low Speed



- Timing margin deceases by 1% UI from 10³ bits to 10¹⁶ bits
- At low speed, limited number of bits is adequate for system verification

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ISI at High Speed

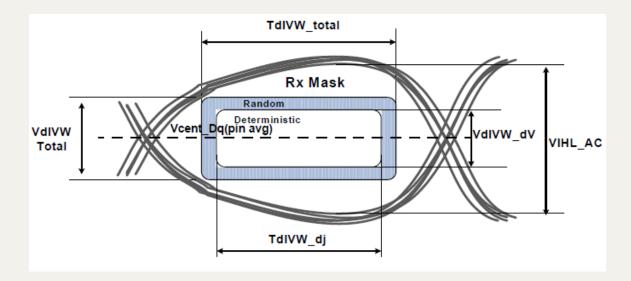


3200 Mb/s

- Timing margin deceases by 9% UI from 10³ bits to 10¹⁶ bits
- At high speed, design needs to be verified at target BER

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DQ Rx Mask Spec in DDR4



- Mask consists of deterministic and random portions
- BER inside the total mask must be below 10⁻¹⁶

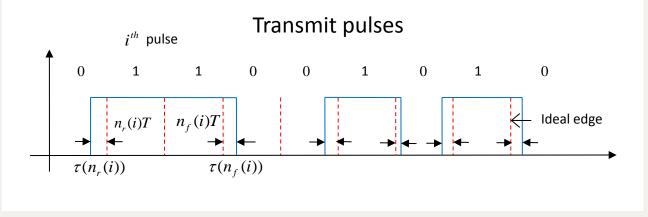
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Statistical Simulation for BER

- It's impractical to simulate 10¹⁶ bits to estimate BER at 10⁻¹⁶
- Statistical method can be employed to calculate eye probability distributions
- Equivalent to running infinite number of bits
- BER can be obtained rigorously at arbitrarily low level

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Linear Superposition



$$v(t) = \sum_{i} \left\{ R[t - n_r(i) \cdot T - \tau(n_r(i))] - F[t - n_f(i) \cdot T - \tau(n_f(i))] \right\} + v_0$$

R(t): rise edge step response F(t): fall edge step response T: UI

 τ : transmitter jitter

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Transmitter Jitter

Jitter components include DCD, SJ and RJ

$$\tau(n_r) = -\frac{DCD_{pp}^{data}}{2} - (-1)^{n_r} \frac{DCD_{pp}^{clk}}{2} + Asin(2\pi f n_r T + \phi) + \rho(n_r)$$

$$\tau(n_f) = \frac{DCD_{pp}^{data}}{2} - (-1)^{n_f} \frac{DCD_{pp}^{clk}}{2} + Asin(2\pi f n_f T + \phi) + \rho(n_f)$$

 DCD_{pp}^{data} : peak-to-peak data DCD DCD_{pp}^{clk} : peak-to-peak clock DCD A & f: SJ amplitude and frequency ρ : RJ

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Eye Probability Distribution

 $p(v,t) = \frac{1}{2\pi} \int_0^{2\pi} d\phi \frac{1}{2^M} \sum_{m=1}^{2^m} \int \delta[v - v^{(m)}(t)] \cdot \prod_i g[\rho(n_r^{(m)}(i))] \cdot g[\rho(n_f^{(m)}(i))] \cdot d\rho(n_r^{(m)}(i)) \cdot d\rho(n_f^{(m)}(i))$

m: pattern indexM: step response settle time in bitg: RJ PDF

- Tx jitter affects the output distribution through channel step responses
- Jitter effect is directly handled in PDF calculation instead of post-processing
- PDF is computed rigorously using efficient algorithms w/o approximation
- Accurate prediction of BER

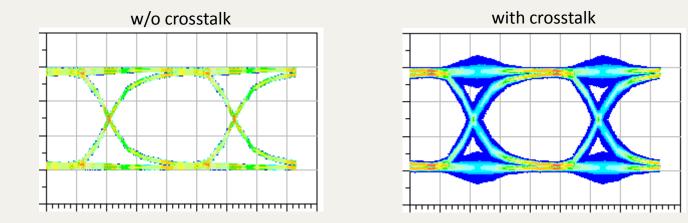
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Crosstalk

Crosstalk is additive noise to victim signal

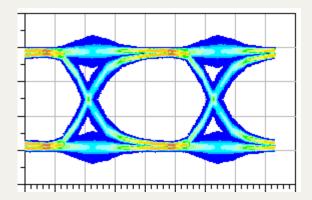
Included by convolution between victim PDF and crosstalk PDF

 $p(v,t) = \int p_{victim}(v - v_1 - v_2 \cdots - v_n, t) p_{xtlk}^{(1)}(v_1, t) p_{xtlk}^{(2)}(v_2, t) \cdots p_{xtlk}^{(n)}(v_n, t) dv_1 dv_2 \cdots dv_n$



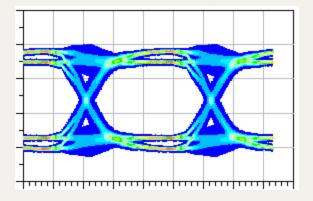
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Driver De-emphasis



w/o de-emphasis

3dB de-emphasis

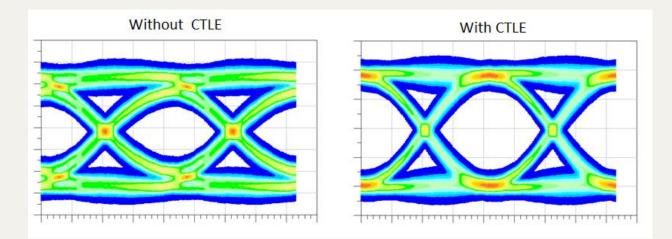


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Rx CTLE

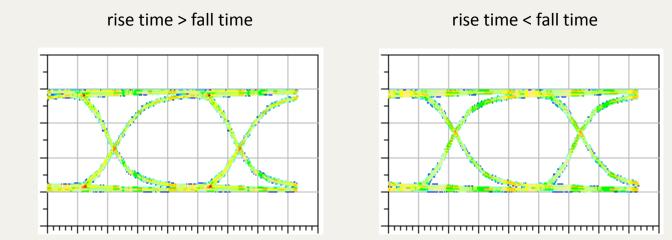
$$H(s) = A \frac{(s - z_1) \dots (s - z_n)}{(s - p_1) \dots (s - p_k)}$$



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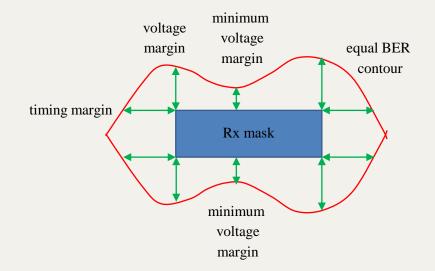
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Asymmetric Rise and Fall Edges Capability



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Timing and Voltage Margins

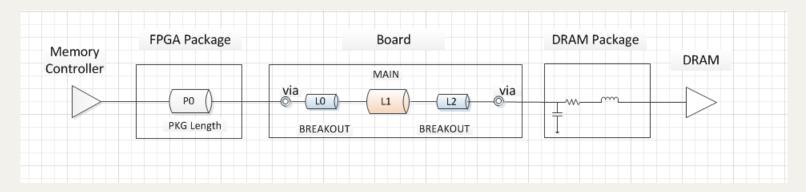


- Timing and Voltage margins are measured at each mask corner
- Ring-back is captured by minimum voltage margins

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DDR4 Channel Topology





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CTLE Optimization

> CTLE design parameters

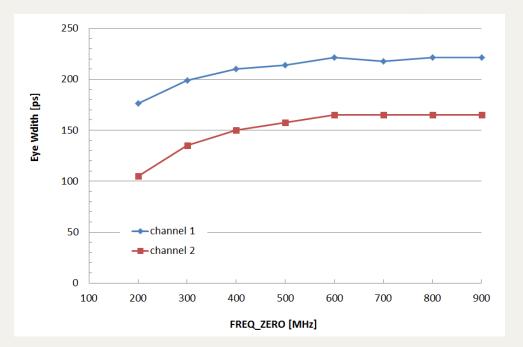
- fz (zero), fp1 (first pole), fp2 (second pole), Gain_dc (dc gain)

$$H_{CTLE}(s) = c \frac{(s+w_zero)}{(s+w_pole1)(s+w_pole2)}$$
$$c = Gain_dc \frac{w_pole1*w_pole2}{w_zero}$$

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CTLE Optimization

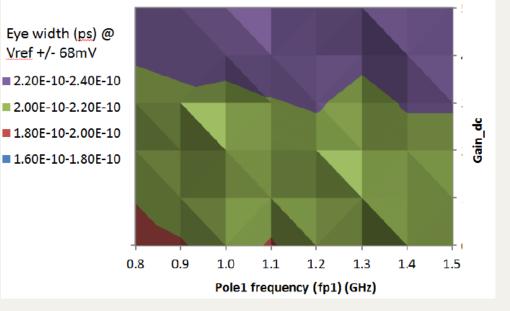
- CTLE fz sensitivity sweep for two study channels
 - BER 10⁻¹⁶ eye width @ Vref
 +/-68mV saturated after
 600Mhz fz



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CTLE Optimization

- CTLE fp1 Vs. Gain_dc sensitivity sweep at 4.5GHz bandwidth
 - BER 10⁻¹⁶ eye width not sensitive to fp1 around 1.2GHz
 - BER 10⁻¹⁶ eye width increase with higher Gain_dc

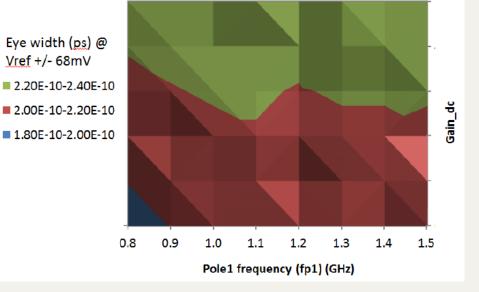


BER 10-16 eye width from fp1 and gain_dc at 4.5GHz bandwidth (fp2)

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CTLE Optimization

- CTLE fp1 Vs. Gain_dc sensitivity sweep at 6 GHz bandwidth
 - BER 10⁻¹⁶ eye width not very sensitive to fp2 around 5GHz
 - BER 10⁻¹⁶ eye width increase with higher Gain_dc

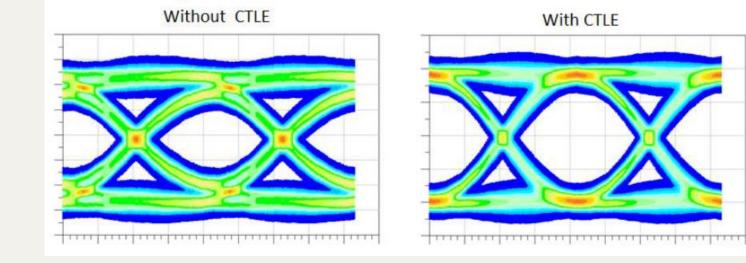


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CTLE Optimization -- 2400Mbps DDR4

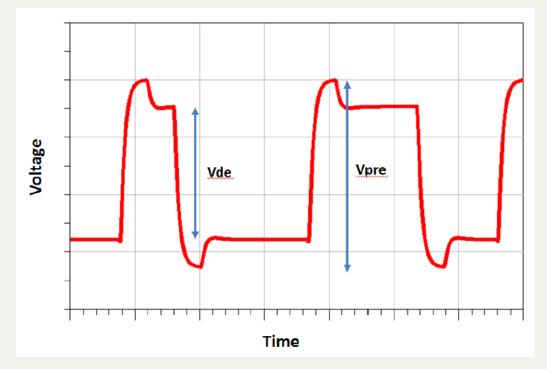
significant BER 10⁻¹⁶ eye width gain achieved with optimized CTLE



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De-emphasis Optimization

De-emphasis dB level is defined as 20*log(Vde/Vpre)

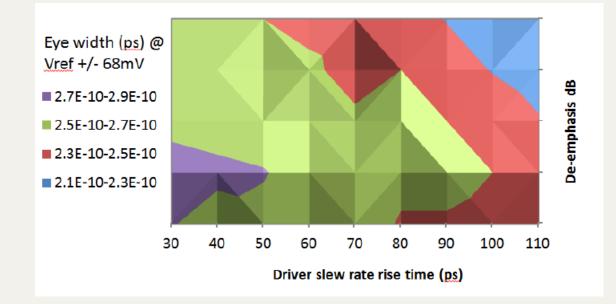


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De-emphasis Optimization

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> Optimal De-emphasis dB can be identified for driver slew rate

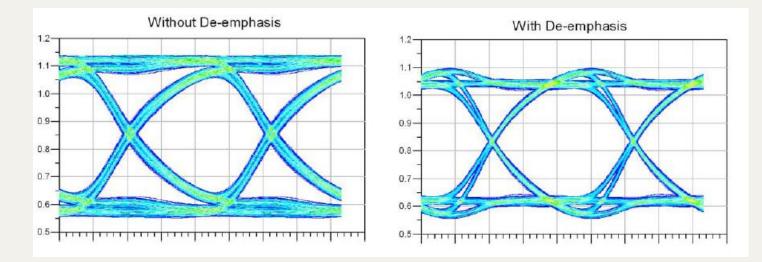


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De-emphasis Optimization – 2400Mbps DDR4

> 10-20ps BER 10⁻¹⁶ eye width gain achieved with optimized dB setting



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Summary

- A statistical simulation engine is introduced for designing DDR4 system to JEDEC 10-16 BER target
- Effects of driver de-emphasis and Rx CTLE on DDR4 timing at BER target of 10-16 are investigated
- > De-emphasis and CTLE are effective techniques to mitigate jitter and achieve DDR4 design target after optimization.